



APPLICATION DATA SHEET

Electronic Version 0.0.11

Stylesheet Version: 1.0

Attorney Docket Number: 740756-2632

Publication Filing Type: new-utility

Application Type: utility

Title of Invention: ELECTRICAL INSPECTION METHOD AND METHOD OF FABRICATING SEMICONDUCTOR DISPLAY DEVICES

Suggested Representative Figure: Fig. 1

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22204

Foreign Priority:

2002-218705

JP 2002-07-26

Priority Claimed

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